Attorney's Docket No.: 07977-126004 / US3269/3270D1D1D1

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: S. Yamazaki, et al. Art Unit: Unknown Serial No.: New Divisional Application Examiner: Unknown

Filed : August 26, 2003

Title : SEMICONDUCTOR THIN FILM AND ITS MANUFACTURING METHOD

AND SEMICONDUCTOR DEVICE

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Copies of the references listed on the attached form PTO-1449 are enclosed.

Under 35 USC §120, this application relies on the earlier filing date of application serial number 10/077/141, filed on February 15, 2002. The cited references were submitted to and/or cited by the Office in the prior application and, therefore, are not provided in this application.

This statement is being filed with the application. Please apply any charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

Date: 8 26 03

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JFH/adt 40172718.doc

1	Substitute Form PTO-1449 U.S. Department of Commerce Patent and Trademark Office		Attorney's Docket No. 07977-126004	Application No.	
İ	Inf rmati n Disclosure Statement by Applicant (Use several sheets if necessary)		Applicant S. Yamazaki et al.		
1			Filing Date	Group Art Unit	
	(37 CFR §1.98(b))				

	U.S. Patent Documents						
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	4,907,053	03/1990	Ohmi			
	AB	5,042,918	08/1991	Suzuki			
	AC	5,274,485	12/1993	Narita et al.			
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	Foreign Patent Documents or Published Foreign Patent Applications							
Examiner	Desig.	Document	Publication	Country or			Trans	slation
Initial	ID	Number	Date	Patent Office	Class	Subclass	Yes	No
	AW	06-232059	08/19/1994	JAPAN			Yes	
	AX	06-244103	09/02/1994	JAPAN			Abst.	

ſ	Examiner Signature	Date Considered
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1	EXAMINER: Initials citation considered. Draw line through citation if no	t in conformance and not considered. Include copy of this form with
l	next communication to applicant.	

	Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 07977-126004	Application No.	
	Information Disclosure Statement by Applicant (Use several sheets if necessary)		Applicant S. Yamazaki et al.		
1			Filing Date	Group Art Unit	
Į	(37 CFR §1.98(b))				

	Foreign Patent Documents or Published Foreign Patent Applications							
Examiner	Desig.	Document	Publication	Country or			Trans	lation
Initial	ID	Number	Date	Patent Office	Class	Subclass	Yes	No
	AY	07-321339	12/08/1995	JAPAN			Abst.	
	BA	08-255916	10/1/1996	JAPAN			Abst.	

	Other Documents (include Author, Title, Date, and Place of Publication)					
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	ВВ	Takahashi, et al., "Oxide-semiconductor interface roughness and electrical properties of polycrystalline silicon thin-film transistors", Appl. Phys. Lett., Vol. 64, No. 17, pp. 2273-2275, April 25, 1994.				
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	BD	Shimokawa, et al., "Characterization of High-Efficiency Cast-Si Solar Cell Wafers by MBIC Measurement", Japanese Journal of Applied Physics, Vol. 27, No. 5, pp. 751-758, May 1988.				
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	BF	Wolf, S., "Silicon Processing for the VLSI Era Volume 3: The Submicron MOSFET", Sunset Beach, CA, p. 648.				

Examiner Signature	Date Considered					
EVAMINED: Initials sitetion considered Drawling theory history if						
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with						
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